

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
216450US0DIVSERIAL NO.
09/994,613

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Kenichi HINOFILING DATE
November 28, 2001GROUP
1714

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
P.S.	AA	4,668,712	05/26/87	HINO, et al.	522	13	
P.S.	AB	6,168,431	01/02/01	NARUSAWA, et al.	433	226	
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO					
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

Peter Snekels

Date Considered

4/18/03

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

216450US0DIV

SERIAL NO.

NEW APPLICATION

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Kenichi HINO

FILING DATE

HEREWITH

10971 U.S. 11/28/01
09/994613

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>P.S.</i>	AA	5,264,513	11/23/93	Kunio IKEMURA, et al.	523	116	
<i>P.S.</i>	AB	4,719,149	01/12/88	Steven M. AASEN, et al.	523	116	
<i>P.S.</i>	AC	6,051,626	04/18/00	W. ZENG, et al.			
<i>P.S.</i>	AD	5,525,648	06/11/96	Steven M. AASEN, et al.			
<i>P.S.</i>	AE	5,321,053	06/14/94	HINO, et al.			
	AF						
	AG						
	AH						
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO	
	AO	WO 93/12760	07/08/93	WIPO (with corr. US 5,525,648)		
	AP	0 835 646	04/15/98	EUROPE (with corr. US 6,051,626)		
	AQ	2 332 911	07/07/99	GREAT BRITAIN		
	AR	3-240712	10/28/91	JAPAN (w/English Abstract)		x
	AS	62-223289	10/01/87	JAPAN (w/English Abstract)		x
	AT	60-45510	03/12/85	JAPAN (w/English Abstract)		x
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

Examiner

Peter Seefeld

Date Considered

4/16/03

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.